Abstracts

A Programmable Load for Power and Noise Characterization

B.W. Leake. "A Programmable Load for Power and Noise Characterization." 1982 MTT-S International Microwave Symposium Digest 82.1 (1982 [MWSYM]): 348-350.

A digitally-controlled one-port tuner, providing sixty-four distinct impedances, has been used to examine the relationship between nonlinear power transistor performance and load impedance. In a similar way, the noise parameters of low noise linear transistors have been deduced from measurements using the tuner to control source impedance. All control, measurement and data reduction functions are performed with a desktop computer.

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